



FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE List of Information Cited by Applicant Page 1 of 1	ATTY. DOCKET NO. SURR.69/C	SERIAL NO. 10/798,196
	APPLICANT STONAS ET AL.	
	FILING DATE MARCH 11, 2004	GROUP 1753

U.S. PATENT DOCUMENTS							
EXAM. INITIAL		DOCUMENT NUMBER	DATE	NAME	CLS	SUB- CLS	FILE DATE
	AA						
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FOREIGN PATENT DOCUMENTS							
EXAM. INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLS	SUB CLS	TRANS ?
	AO						
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
<i>DOU</i>	AXX	DOUDIN ET AL. (1995) NANOSTRUCTURED MATERIALS 6:521-524
<i>AG</i>	AYX	NAGODAWITHANA ET AL. (1995) ELECTROCHEMICAL SOCIETY PROCEEDINGS 95:8-237
	AAA	
EXAMINER	<i>Opheaz</i>	
	DATE CONSIDERED	<i>9/30/07</i>
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EXAM. INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLS	SUB CLS	TRANS ?
<i>APB</i>	AO	WO 99/54786	10/28/99	PCT			
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
<i>APB</i>	<input checked="" type="checkbox"/> <i>AX</i>	JACKMAN ET AL. (1999) LANGMUIR 15:2973-2984
	<input type="checkbox"/> <i>AY</i>	
	<input type="checkbox"/> <i>AAA</i>	
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EXAM. INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLS	SUB CLS	TRANS ?
<i>DS</i>	AK	WO 99/41006	08/19/1999	WIPO			
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	AS						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
<i>DS</i>	<i>AD</i>	Leong et al., Journal of Controlled Release, 1998, Vol. 53, p. 183-193
	AU	
	AAA	
EXAMINER <i>apthasge</i>		DATE CONSIDERED <i>9/30/07</i>
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U.S. PATENT DOCUMENTS							
EXAM. INITIAL		DOCUMENT NUMBER	DATE	NAME	CLS	SUB- CLS	FILE DATE
<i>DD</i>	AA	3,755,730	08/28/73	Vogelgesang			
	AB	3,878,367	04/15/75	Fayling et al.			
	AC	3,897,284	07/29/75	Livesay			
	AD	4,053,433	10/11/77	Lee			
	AE	4,098,935	07/04/78	Knudsen			
	AF	4,131,064	12/26/78	Ryan et al.			
	AG	4,306,993	12/22/81	Danielson et al.			
	AH	4,329,393	05/11/82	LaPerre			
	AI	4,390,452	06/28/83	Stevens			
	AJ	4,397,142	08/09/82	Bingham			
	AK	4,469,623	09/04/84	Danielson et al.			
	AL	4,527,383	07/09/85	Bingham			
	AM	4,679,939	07/14/87	Curry et al.			
<i>DD</i>	AN	4,855,930	08/08/89	Chao et al.			

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EXAM. INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLS	SUB CLS	TRANS ?
<i>DD</i>	AO	WO 97/15390	05/01/97	PCT			
	AP	WO 99/18240	04/15/99	PCT			
	AQ	WO 99/47253	09/23/99	PCT			
	AR	WO 99/64580	12/16/99	PCT			
	AS	WO 00/63419	10/26/00	PCT			
	AT	WO 01/26038	04/12/01	PCT			
	AU	WO 01/25002	04/12/01	PCT			
	AV	WO 01/25510	04/12/01	PCT			
<i>DD</i>	AW	EP 1018365	07/12/00	EUROPE			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)				
<i>DD</i>	AX	Al-Mawlawi et al. (1991) J. Appl. Phys. 70(8):4421-4425		
<i>DD</i>	AY	Al-Mawlawi et al. (1994) J. Mater. Res. 9:1014		
<i>DD</i>	AA	Al-Rawashdeh et al. (1998) J. Phys. Chem. B. 102:361-371		
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EXAM. INITIAL		DOCUMENT NUMBER	DATE	NAME	CLS	SUB- CLS	FILE DATE
<i>PS</i>	BA	4,884,886	12/05/89	Salzman et al.			
	BB	5,091,188	02/25/92	Haynes et al.			
	BC	5,303,710	04/19/94	Bashkansky et al.			
	BD	5,449,565	09/12/95	Aoki et al.			
	BE	5,547,748	08/20/96	Ruoff et al.			
	BF	5,508,164	04/16/96	Kausch et al..			
	BG	5,512,131	04/30/96	Kumar and Whitesides			
	BH	5,547,849	08/20/96	Baer et al.			
	BI	5,556,764	09/17/96	Sizto et al.			
	BJ	5,571,726	11/05/96	Brooks, et al.			
	BK	5,599,615	02/04/97	Swift et al.			
	BL	5,645,619	07/08/97	Erickson et al.			
	BM	5,674,743	10/07/97	Ulmer			
	BN	5,667,667	09/16/97	Southern			
	BO	5,732,150	03/24/98	Zhou et al.			
	BP	5,846,517	12/08/98	Unger			
	BQ	5,859,700	01/12/99	Yang			
	BR	5,927,621	07/27/99	Ziolo and Pieczynski			
	BS	5,985,356	11/16/99	Schultz et al.			
	BT	5,997,958	12/07/99	Sato et al.			
	BU	6,020,419	02/01/00	Bock et al.			
	BV	6,071,336	06/06/00	Fairchild and Thatcher			
	BW	6,093,302	07/25/00	Montgomery et al.			
	BX	6,132,278	10/17/00	Kang et al.			
	BY	6,143,211	11/07/00	Mathiowitz et al.			
	BZ	6,162,532	12/19/00	Black et al.			
<i>PS</i>	BAA	6,172,902	01/09/01	Wegrowe et al.			
	BBB	6,334,856	01/01/02	Allen et al.			

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<i>PS</i>	BCS <input checked="" type="checkbox"/> Blondel et al. (1994) Applied Physics Letters 65:3019-3021
<i>PS</i>	BDD <input checked="" type="checkbox"/> Braun et al. (1999) Nature 402-603
EXAMINER	<i>CPHasege</i> DATE CONSIDERED <i>9/30/07</i>
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Ref	CA	Braeckmans et al. (2001) Poster Presented at the Drug Discovery Technology Conference
	CB	Brumlik et al. (1991) J. Am. Chem. Soc. 113:3174
	CC	Bruchez, Jr. et al. (1998) Science 281:2013-2016
	CD	Cepak and Martin (1998) J. Phys. Chem. B102:9985
	CE	Cepak and Martin (1999) Chem. Mater. 11:1363
	CF	Cepak et al. (1997) Chem. Mater. 9:1065-1067
	CG	Davis et al. (1998) Chem. Mater. 10:2516
	CH	Decker et al. (1997) J of Vacuum Science and Technology: Part B 15(6):1949-1953
	CI	Dermody et al. (1999) Abstracts of Papers American Chemical Society 217(1-2):PANYL 137
	CJ	Dietz et al. (1996) Cytometry 23:177-186
	CK	El-Kouedi and Foss, Jr. (2000) J. Phys. Chem. 104:4031-4037
	CL	El-Kouedi et al. (1998) Chem. Mater. 10:3287
	CM	Foss et al. (1992) J. Phys. Chem. 96:9001-9007
	CN	Foss et al. (1994) J. Phys. Chem. 98:2963
	CO	Hornyak et al (1997) J. Phys. Chem. 101:1548-1555
	CP	Hulteen et al (1997) J. Mater. Chem. 7:1075
	CQ	Jirage et al. (1997) Science 278:655-658
	CR	Keating et al. (2000) Abstract Papers – American Chemical Society V220, PU429-U429
	CS	Keating et al. (2000) Presentation at Electrochem' 2000
	CT	Lehninger (1970) Biochemistry pg 640, The Molecular Basis of Cell Structure and Function
	CU	Liu et al. (1995) Physical Review B, 51(11):7381-7384
	CV	Mallouk et al. (2000) Abstract Papers – American Chemical Society V220, PU440-U440
	CW	Martin (1995) Acc. Chem. Res. 28:61-68
	CX	Martin (1996) Chem. Mater. 8:1739
	CY	Martin (1990) J. Am. Chem. Soc. 112:8976
	CZ	Martin (18 Aug 1999) Adv. Mater. 11:1021
	CCA	Mbdinyo et al. (2000) Abstract Papers- American Chemical Society V220, IEC-187
	CCB	McDade and Fulton (1997) Medical Device and Diagnostic Industry 19:75
	CCC	Meng et al. (1998) Solid State Communications 106:215
	CCD	Merchant (2000) Electrophoresis 21:1164-1167
	CCE	Michael et al. (1998) Anal. Chem. 70:1242
Ref	CCF	Nakajima et al. (1994) Japanese Journal of Applied Physics 33(12B):L1796-L1798
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DA	X	Natan et al. (2000) Presentation at CHI's 4 th Annual Advances in Labels, Signaling and Detection
DB	X	Nishizawa et al. (1995) Science 268:700-702
DC	X	Penner et al. (1987) Anal. Chem. 59:2625-2630
DD	X	Piatek et al. (1998) Nature Biotechnology 16:359
DE	X	Piriaux et al. (1994) Applied Physics Letters 65:2484-2486
DF	X	Piriaux et al. (1999) J. Mater. Res. 14(7):3042-3050
DG		Polla et al. (2002) Nanolithography Structures Materials and their Applications in Biothechnology, Third International Conference on Synchrotron Radiation in Materials Science (SRMS-3), Singapore, January 21-24, 2002.
DH	X	Reiss et al. (1998) Abstracts of Papers of the American Chemical Society 216:P173-COLL
DI	X	Reiss et al. (1998) 72 nd Colloid and Surface Science Symposium, American Chemical Society, University Park, PA
DJ	X	Reiss et al. (2000) Abstracts of Papers - American Chemical Society V220, PHYS-572
DK	X	Routkevitch et al. (1996) J. Phys. Chem. 100(33):14037-47
DL	X	Sandrock et al. 1999 J. Phys. Chem. B 103:11398-11406
DM	X	Sapp et al. (1999) Chem. Mater. 11:1183-85
DN	X	Savas et al. (1996) J. Vac. Sci. Tech B 14:4167
DO	X	Savas et al. (1999) J. Applied Physics 85:6160
DP	X	Schwarzacher (1999) Electrochemical Society Interface 20-24
DQ	X	Tiernay et al. (1989) J. Phys. Chem. 93:2878-2880
DR		Ting (2001) Collaboration Opportunities, non-confidential presentation, December 06, 2001
DS	X	Van der Zande et al. (1997) J. Phys. Chem. B 101:852
DT	X	Wang et al. (1996) Thin Solid Films 288:86
DU	X	Wolf and Tauber (2000) Silicon Processing for the VLSI Era, Vol. 1 Process Technology (2 nd Ed.) Lattice Press, California (Table of Contents Only)
DV	X	Wong et al. (1996) Chem. Mater. 8:2041
DW	X	Zhang et al. (1999) Chem. Mater. 11:1659
DX		
DY		
DZ		
CCC		
CCD		
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